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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Patent**

Applicant(s): Keiji YADA, et al. ) Re: Information Disclosure  
Serial No.: 10/719,887 ) Statement  
Filed: November 21, 2003 ) Group: not yet assigned  
For: "X-RAY MICROSCOPIC INSPECTION )  
APPARATUS" ) Examiner: not yet assigned  
  ) Our Ref: B-5308 621524-7  
  ) Date: November 10, 2004

Commissioner for Patents  
P.O. Box 1450  
Alexandria VA, 22313-1450

Sir:

In accordance with the Applicants' duty to disclose information which may be material to the examination of this application, the undersigned respectfully requests that the Examiner consider on the merits the documents listed on the enclosed Form PTO-1449 (modified) before issuing the first Office Action on the merits. We are enclosing herewith a copy of each document listed on the enclosed Form PTO-1449 (modified).

The documents listed on the enclosed Form PTO-1449 (modified) include those cited in the European Search Report for the corresponding European Patent Application No. EP 04001489.6. A copy of the Search Report (11 pages) is enclosed herewith.

The filing of this Information Disclosure Statement (IDS) shall not be construed as a representation that a search has been made (37 C.F.R. 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability, or that no other material information exists.

The Applicants believe that this IDS is being submitted before the issuance of a first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance. Therefore,

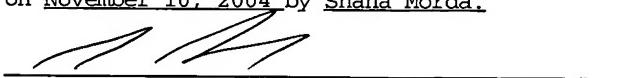
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no official fees should be due; and this IDS should be considered on the merits. If this IDS is being submitted after the issuance of the first Office Action on the merits and before the issuance of a Final Rejection or Notice of Allowance, please contact the undersigned to authorize a payment of \$180.00 (or any other required amount), which is the fee set forth in 37 C.F.R. § 1.97(c), if the Examiner believes that such a fee is due in order for this IDS to be considered on the merits.

The filing of this Information Disclosure Statement shall not be construed as an admission against interest in any manner. (Notice of January 9, 1992, 1135 O.G. 13-25, at 25.)

The person making this statement is the practitioner who signs below on the basis of information supplied by an individual associated with the filing and prosecution of this application (37 C.F.R. § 1.56(c)) and on the basis of information in the practitioner's file.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first-class mail in an envelope addressed to the "Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450", on November 10, 2004 by Shana Morda.



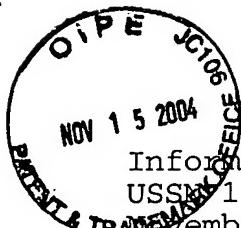
Respectfully submitted,



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Enclosures: Form PTO-1449 (modified) (1 page)  
Copy of Search Report for EP 04001489.6 (11 pages)  
Copy of documents listed on Form PTO-1449 (modified)



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Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5308 621524-7	U.S. SERIAL NO. 10/719,887
LIST OF PATENTS AND PUBLICATIONS STATEMENT	<b>APPLICANTS</b> Keiji YADA, et al.	
	FILING DATE November 21, 2003	GROUP not yet assigned

**U.S. PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB-CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
	865,050	4/1961	GB			
	2 131 224	6/1984	GB			

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

	Delong, A., et al., "A New Design Of Field Emission Electron Gun With A Magnetic Lens," <i>Optik</i> , Vol. 81, No. 3, pp. 103-108 (1989).
	Mayo, S.C., et al., "X-Ray Phase-Contrast Microscopy and Microtomography," <i>Optics Express</i> , Vol. 11, No. 19, pp. 2289-2302 (September 2, 2003).

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.